

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/037,732	HAY, SAM H.
	<b>Examiner</b> Duy M. Dang	<b>Art Unit</b> 2624

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See Interference searched		6/14/2006	DD